

**N-Channel Enhancement Mode Power MOSFET****MTN4N65CFP**

BV_{DSS}	650V
I_D @V_{GS}=10V, T_C=25°C	4A
I_D @V_{GS}=10V, T_C=100°C	2.4A
R_{DS(ON)}@V_{GS}=10V, I_D=2A	1.7Ω (typ)

Description

The MTN4N65CFP is a N-channel enhancement-mode MOSFET, providing the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost effectiveness. The TO-220FP package is universally preferred for all commercial-industrial applications

Features

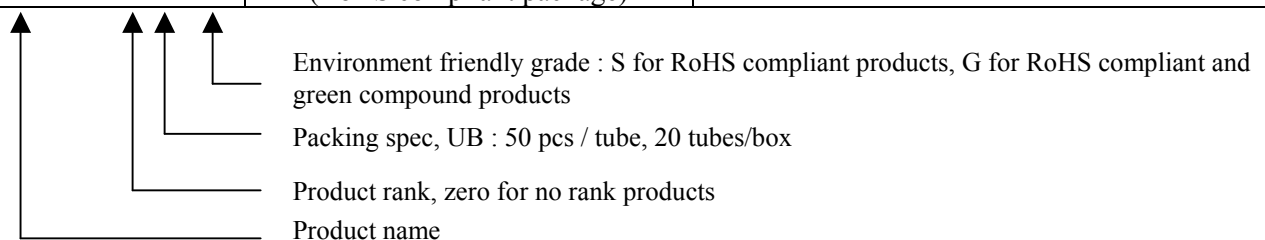
- Low On Resistance
- Simple Drive Requirement
- Fast Switching Characteristic
- Insulating package, front/back side insulating voltage=2500V(AC)
- RoHS compliant package

Applications

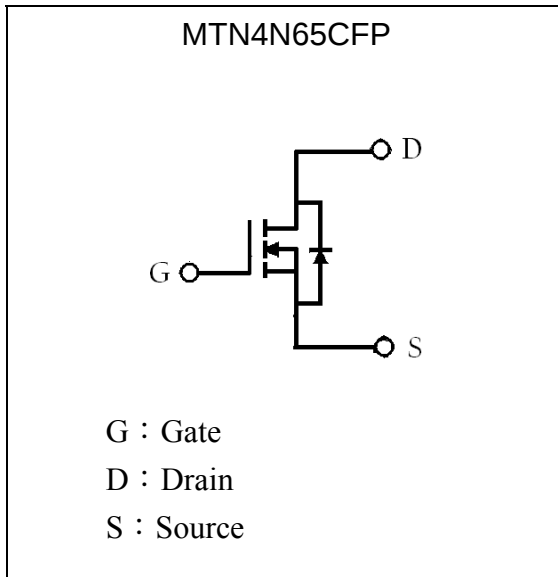
- Adapter
- Switching Mode Power Supply

Ordering Information

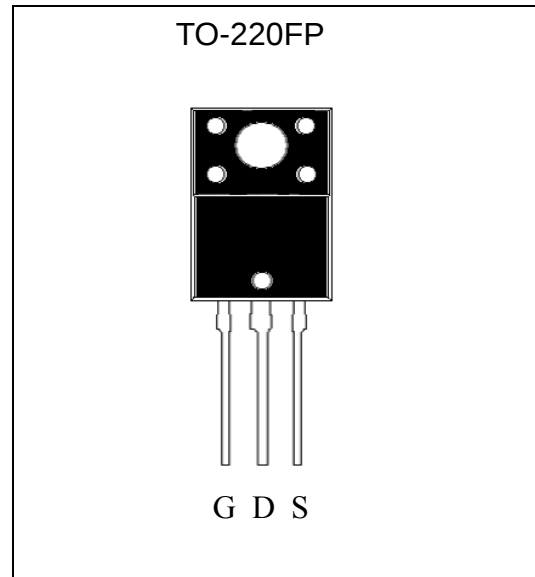
Device	Package	Shipping
MTN4N65CFP-0-UB-S	TO-220FP (RoHS compliant package)	50 pcs/tube, 20 tubes/box, 4 boxes / carton



Symbol



Outline



Absolute Maximum Ratings (T_c=25°C)

Parameter	Symbol	Limits	Unit
Drain-Source Voltage	V _{DS}	650	V
Gate-Source Voltage	V _{GS}	±30	
Continuous Drain Current	I _D	4*	A
Continuous Drain Current @T _c =100°C, V _{GS} =10V		2.4*	
Pulsed Drain Current @ (Note 1)	I _{DM}	16*	
Single Pulse Avalanche Energy (Note 2)	E _{AS}	16	mJ
Avalanche Current (Note 1)	I _{AS}	2	A
Repetitive Avalanche Energy (Note 1)	E _{AR}	3.4	mJ
Maximum Temperature for Soldering @ Lead at 0.125 in(0.318mm) from case for 10 seconds	T _L	300	°C
Total Power Dissipation (T _c =25°C)	P _D	34	W
Linear Derating Factor		0.27	W/°C
Operating Junction and Storage Temperature	T _j , T _{stg}	-55~+150	°C

*Drain current limited by maximum junction temperature

Note : 1.Repetitive rating; pulse width limited by maximum junction temperature.

2. I_{AS}=2A, V_{DD}=50V, L=8mH, V_{GS}=10V, starting T_j=+25°C. 100% tested by conditions of L=8mH, I_{AS}=1.6A, V_{DD}=50V, V_{GS}=10V

**Thermal Data**

Parameter	Symbol	Value	Unit
Thermal Resistance, Junction-to-case, max	$R_{th,j-c}$	3.68	°C/W
Thermal Resistance, Junction-to-ambient, max	$R_{th,j-a}$	62.5	°C/W

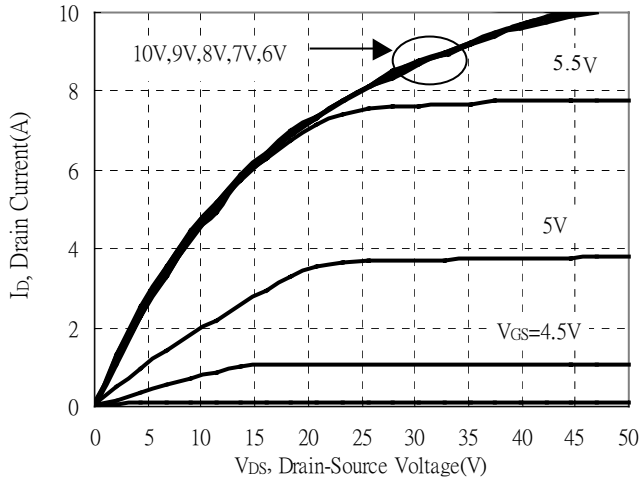
Characteristics (Tj=25°C, unless otherwise specified)

Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Static					
BV _{DSS}	650	-	-	V	V _{GS} =0V, I _D =250μA, T _j =25°C
ΔBV _{DSS} /ΔT _j	-	0.8	-	V/°C	Reference to 25°C, I _D =250μA
V _{GS(th)}	2.0	-	4.0	V	V _{DS} = V _{GS} , I _D =250μA
*G _{FS}	-	4	-	S	V _{DS} =15V, I _D =2A
I _{GSS}	-	-	±100	nA	V _{GS} =±30V
I _{DSS}	-	-	1	μA	V _{DS} =650V, V _{GS} =0V
	-	-	10		V _{DS} =520V, V _{GS} =0V, T _C =125°C
*R _{DS(ON)}	-	1.7	2.3	Ω	V _{GS} =10V, I _D =2A
Dynamic					
*Q _g	-	16.4	-	nC	I _D =4A, V _{DD} =520V, V _{GS} =10V
*Q _{gs}	-	3.5	-		
*Q _{gd}	-	6.1	-		
*t _{d(ON)}	-	10.6	-	ns	V _{DD} =325V, I _D =4A, V _{GS} =10V, R _G =25 Ω
*t _r	-	39	-		
*t _{d(OFF)}	-	21.8	-		
*t _f	-	60.6	-		
C _{iss}	-	614	-	pF	V _{GS} =0V, V _{DS} =25V, f=1MHz
C _{oss}	-	61	-		
C _{rss}	-	13	-		
Source-Drain Diode					
*I _S	-	-	4	A	
*I _{SM}	-	-	16		
*V _{SD}	-	0.79	1.2	V	I _S =2A, V _{GS} =0V
*t _{rr}	-	370	-	ns	V _{GS} =0V, I _F =4A, dI _F /dt=100A/μs
*Q _{rr}	-	1.7	-	μC	

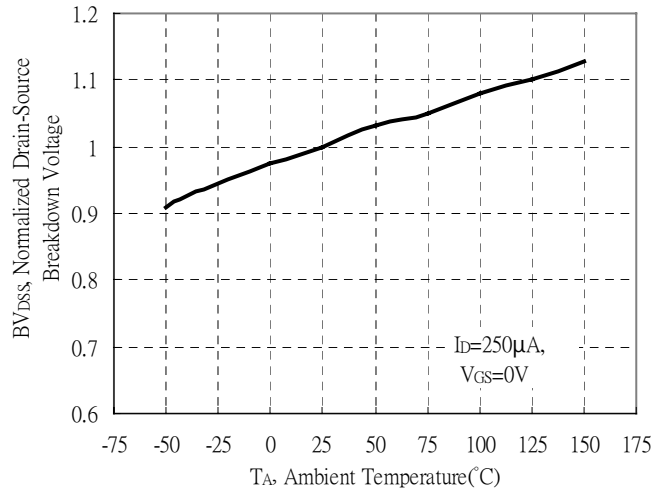
*Pulse Test : Pulse Width ≤300μs, Duty Cycle≤2%

Typical Characteristics

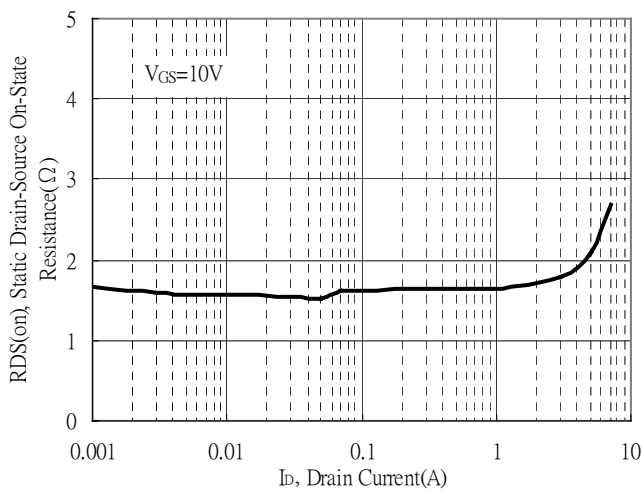
Typical Output Characteristics



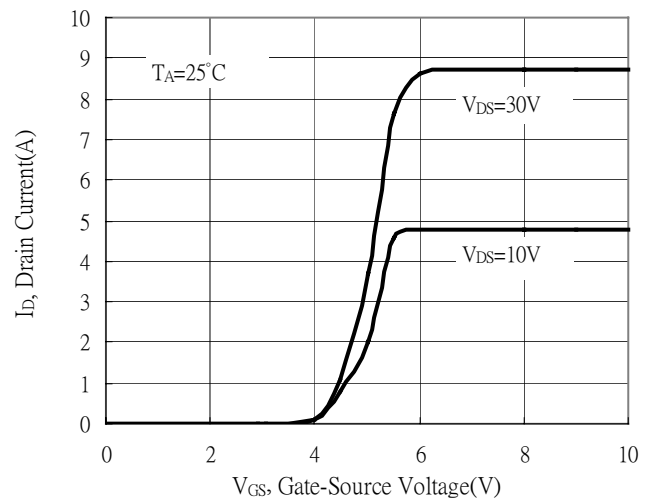
Breakdown Voltage vs Ambient Temperature



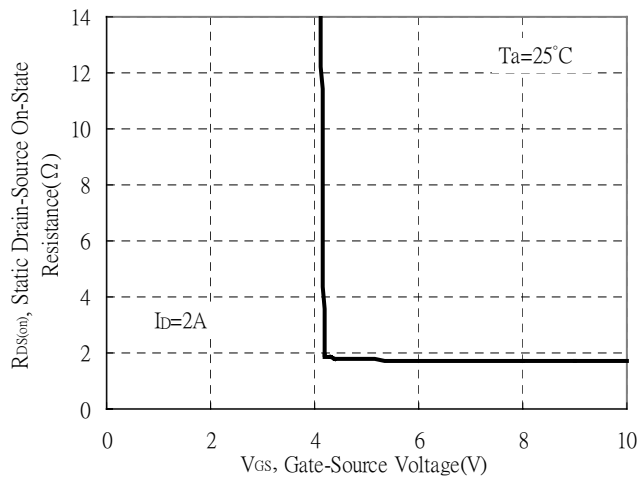
Static Drain-Source On-State resistance vs Drain Current



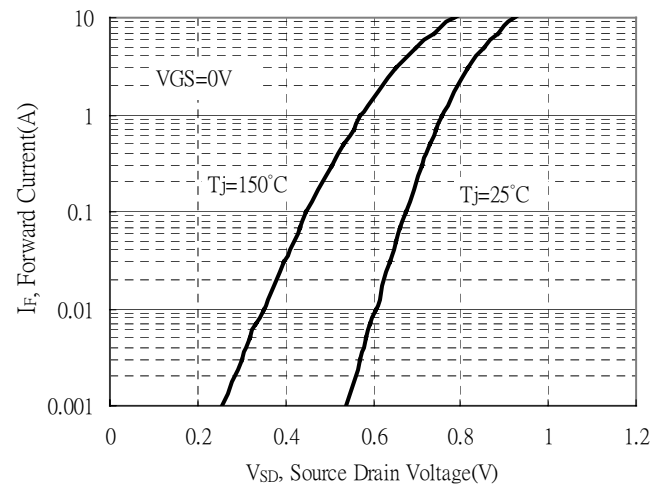
Drain Current vs Gate-Source Voltage



Static Drain-Source On-State Resistance vs Gate-Source Voltage

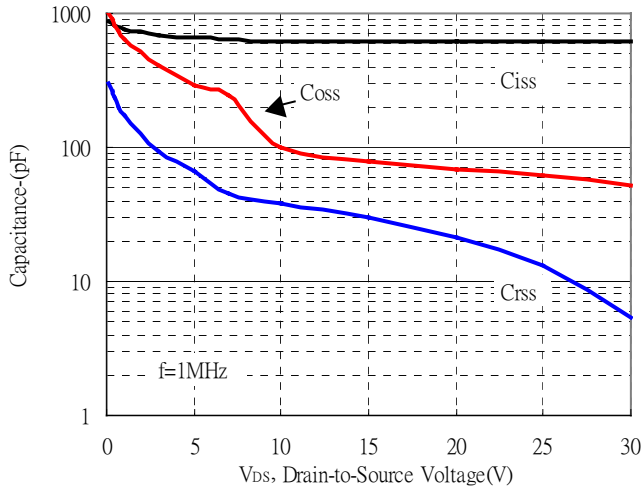


Forward Drain Current vs Source-Drain Voltage

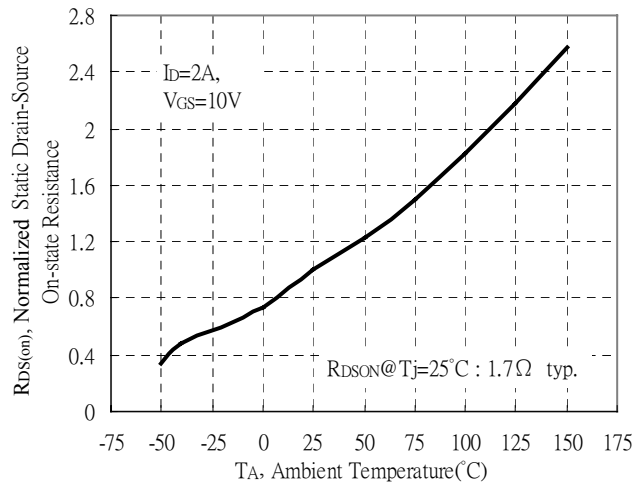


Typical Characteristics(Cont.)

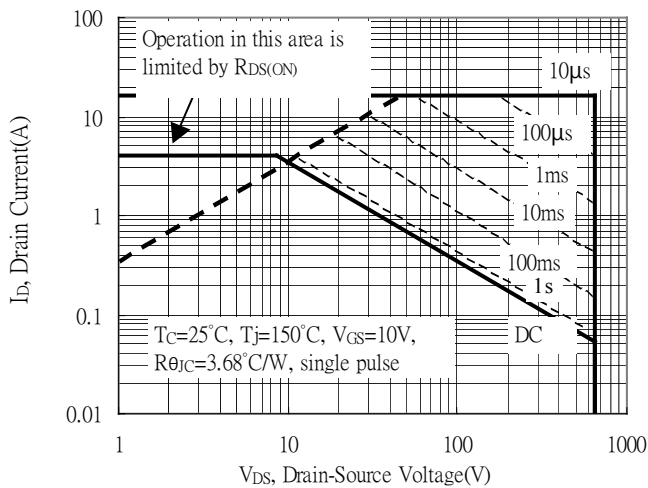
Capacitance vs Reverse Voltage



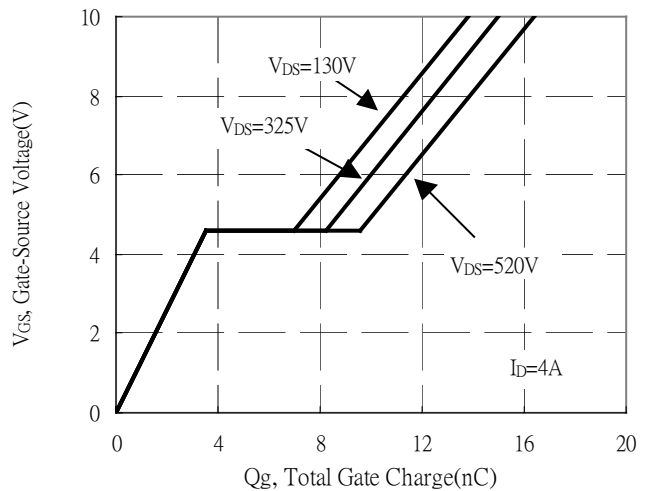
Static Drain-Source On-resistance vs Ambient Temperature



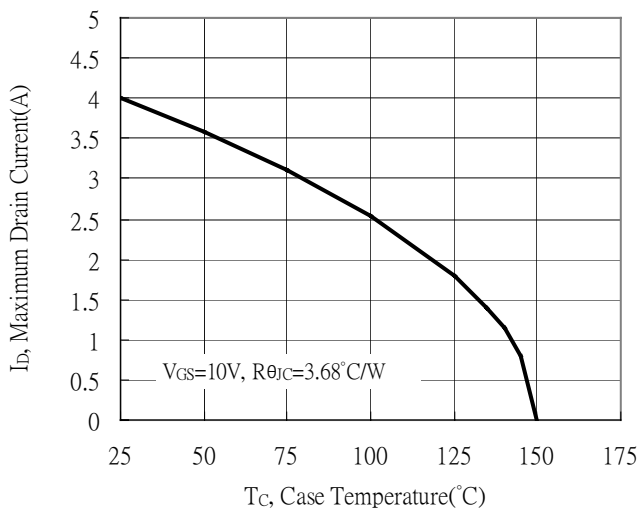
Maximum Safe Operating Area



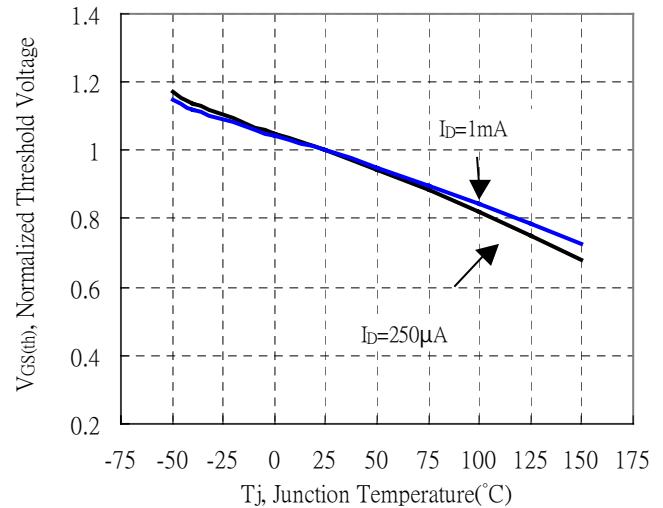
Gate Charge Characteristics



Maximum Drain Current vs Case Temperature

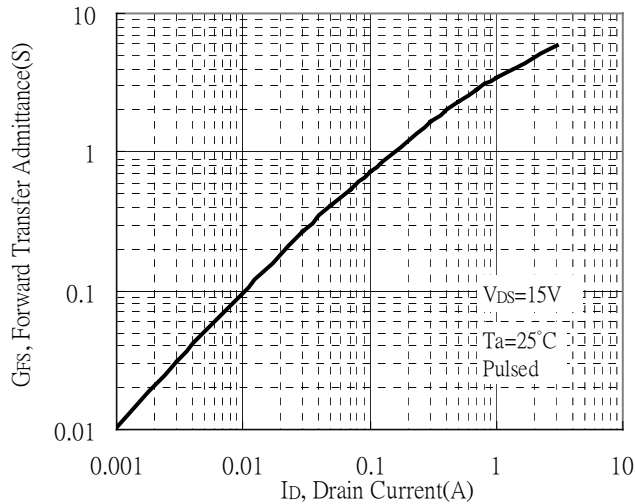


Threshold Voltage vs Junction Temperature

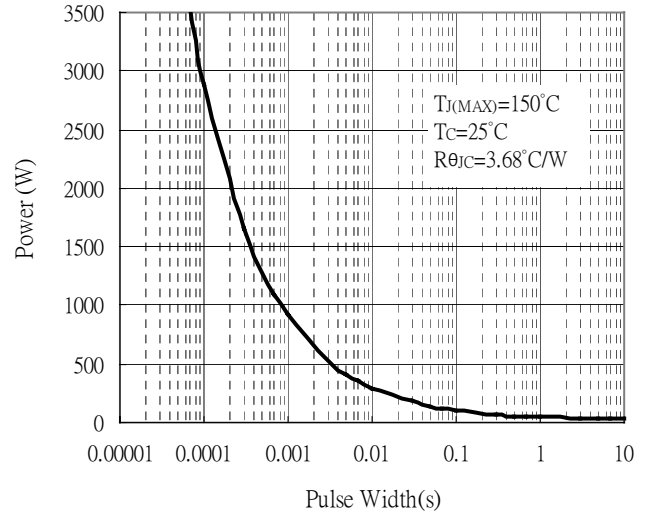


Typical Characteristics(Cont.)

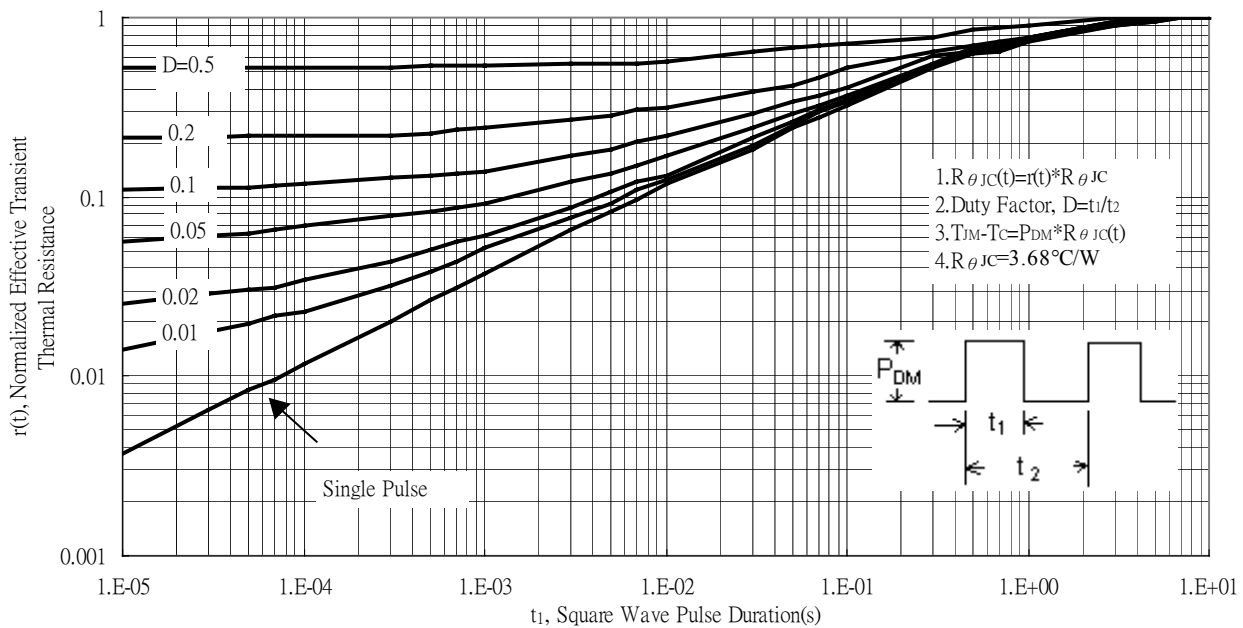
Forward Transfer Admittance vs Drain Current



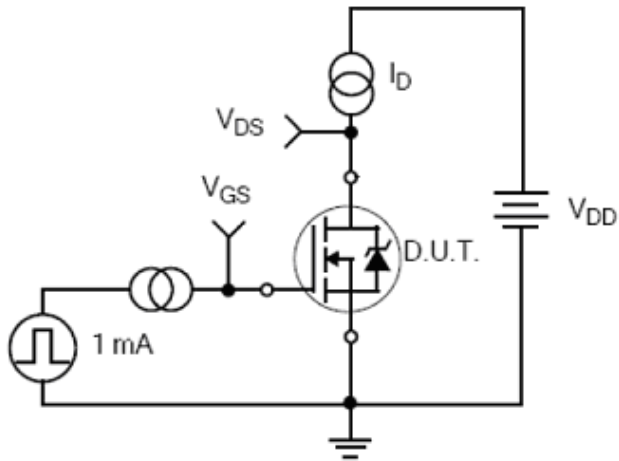
Single Pulse Power Rating, Junction to Case



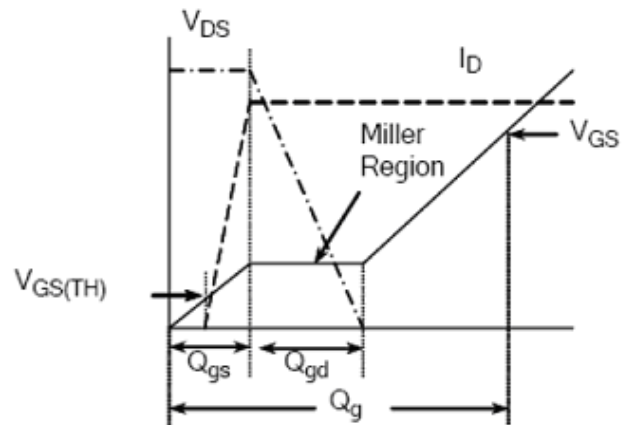
Transient Thermal Response Curves



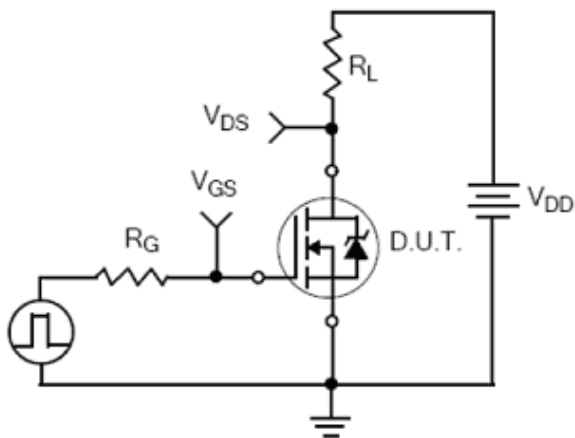
Test Circuit and Waveforms



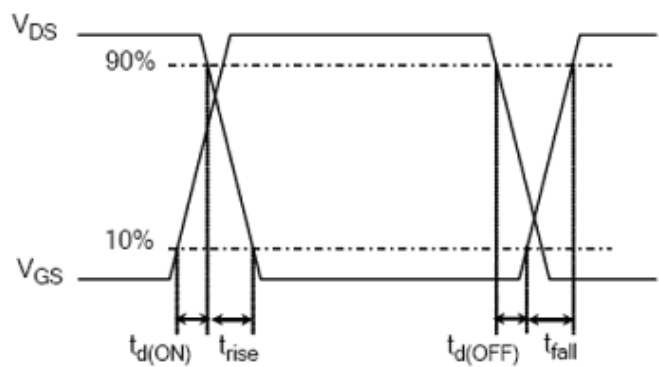
Gate Charge Test Circuit



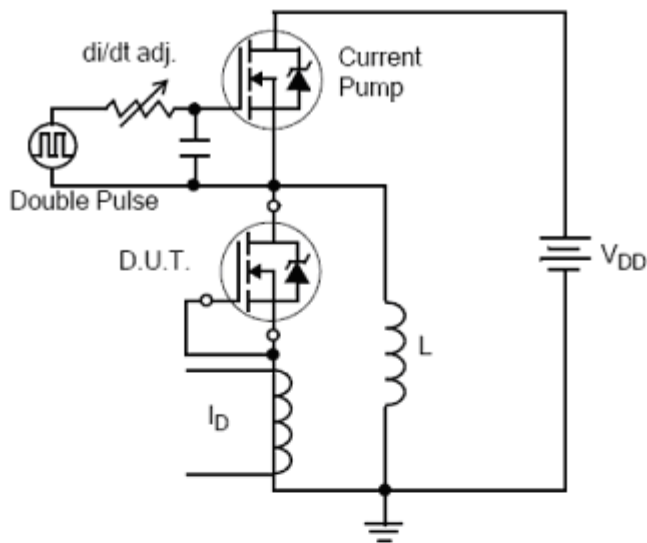
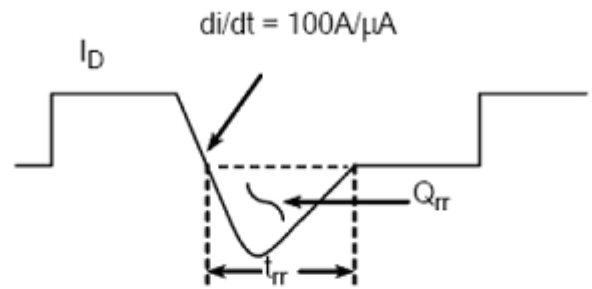
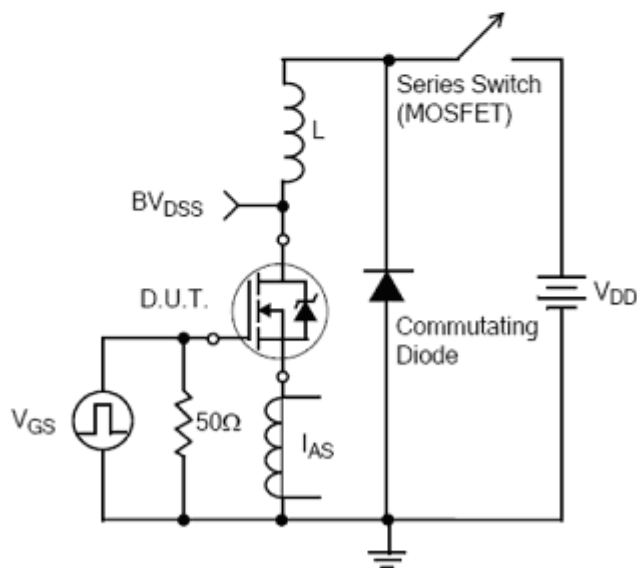
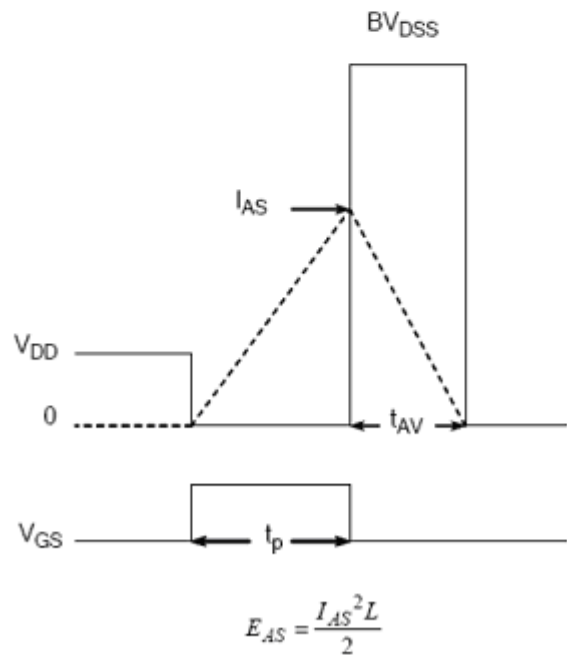
Gate Charge Waveform



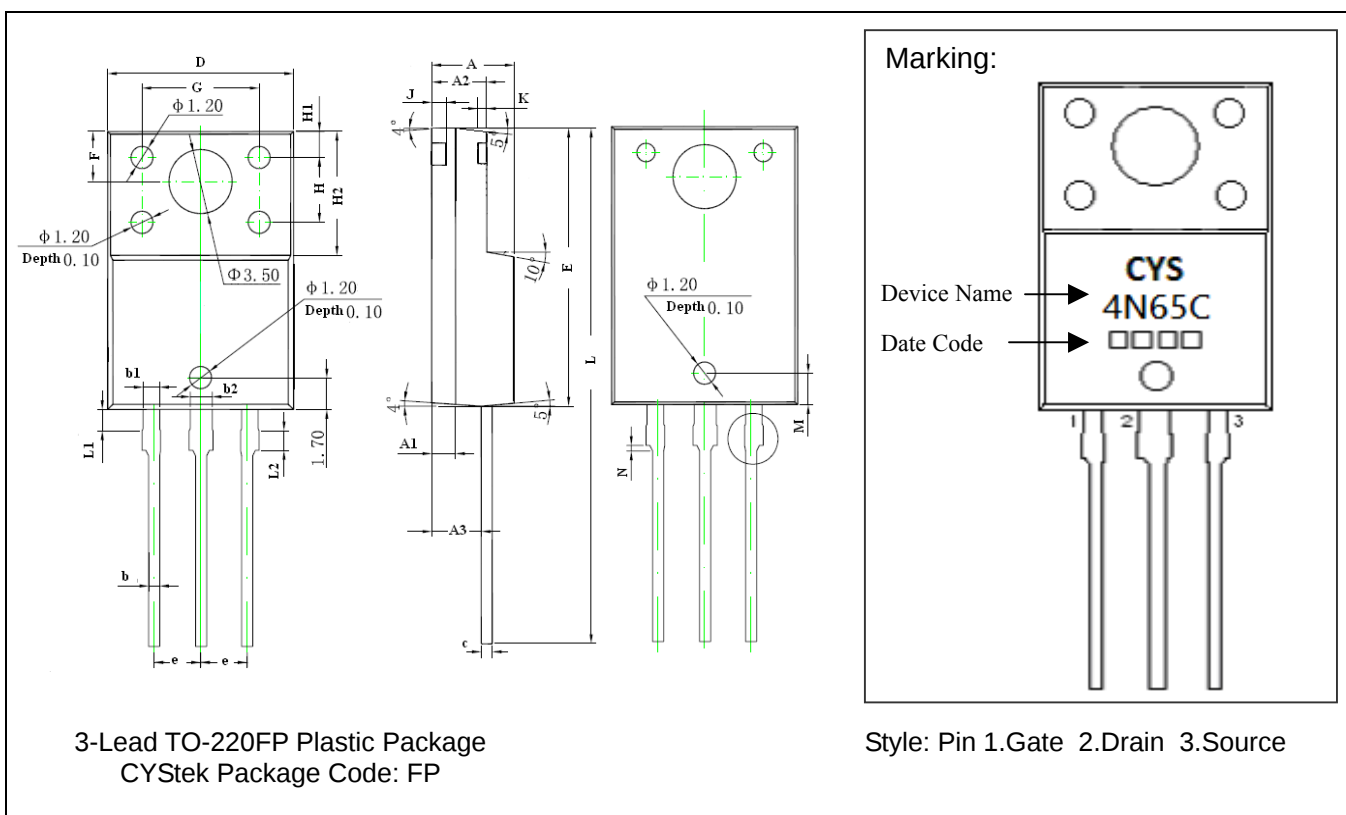
Resistive Switching Test Circuit



Resistive Switching Waveforms

Test Circuit and Waveforms(Cont.)

Diode Reverse Recovery Test Circuit

Diode Reverse Recovery Waveform

Unclamped Inductive Switching Test Circuit

Unclamped Inductive Switching Waveforms

TO-220FP Dimension



*Typical

DIM	Inches		Millimeters		DIM	Inches		Millimeters	
	Min.	Max.	Min.	Max.		Min.	Max.	Min.	Max.
A	0.171	0.183	4.35	4.65	G	0.246	0.258	6.25	6.55
A1	0.051 REF		1.300 REF		H	0.138 REF		3.50 REF	
A2	0.112	0.124	2.85	3.15	H1	0.055 REF		1.40 REF	
A3	0.102	0.110	2.60	2.80	H2	0.256	0.272	6.50	6.90
b	0.020	0.030	0.50	0.75	J	0.031 REF		0.80 REF	
b1	0.031	0.041	0.80	1.05	K	0.020		0.50 REF	
b2	0.047 REF		1.20 REF		L	1.102	1.118	28.00	28.40
c	0.020	0.030	0.500	0.750	L1	0.043	0.051	1.10	1.30
D	0.396	0.404	10.06	10.26	L2	0.036	0.043	0.92	1.08
E	0.583	0.598	14.80	15.20	M	0.067 REF		1.70 REF	
e	0.100 *		2.54*		N	0.012 REF		0.30 REF	
F	0.106 REF		2.70 REF						

Notes: 1.Controlling dimension: millimeters.

2.Maximum lead thickness includes lead finish thickness, and minimum lead thickness is the minimum thickness of base material.

3.If there is any question with packing specification or packing method, please contact your local CYStek sales office.

Material:

- Lead: Pure tin plated.
- Mold Compound: Epoxy resin family, flammability solid burning class: UL94V-0.

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